

**Notice of References Cited**

Application/Control No.

09/706,274

Applicant(s)/Patent Under  
Reexamination  
ARNEY ET AL.

Examiner

Arlen Soderquist

Art Unit

1743

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	K	US-			
	L	US-			
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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